

# Sparse Invariant Risk Minimization

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**Motivation:** How can we address a basic and intractable contradiction between the model trainability and generalization ability in IRM?

## Dilemma

- Large-sized or even overparameterized neural networks are important to make the model easy to train.
- Generalization ability of IRM is much easier to be demolished by overfitting caused by overparameterization.

# Investigating the Effects of Overparameterization on IRM

## Data Generation Process

Two training environments  $\mathcal{E}_{tr} = \{e_1, e_2\}$ .  $\mathbf{x}^e$  the input feature of environment  $e \in \mathcal{E}_{tr}$ , concatenated from invariant feature  $\mathbf{x}_{inv}^e$ , spurious feature  $\mathbf{x}_s^e$  and the random feature  $\mathbf{x}_r^e$ , i.e.,  $\mathbf{x}^e := [\mathbf{x}_{inv}^e, \mathbf{x}_s^e, \mathbf{x}_r^e] \in \mathbb{R}^d$ . The data is generated as follows:

$$\begin{aligned}y^e &= \gamma^\top \mathbf{x}_{inv}^e + \epsilon_{inv}, \\ \mathbf{x}_s^e &= y^e \mathbf{1}^s + \alpha^e \circ \epsilon_s \\ \mathbf{x}_r^e &= \epsilon_r,\end{aligned}$$

where  $e \in \mathcal{E}_{tr}$ ,  $\epsilon_{inv}$ ,  $\epsilon_s$  and  $\epsilon_r$  are independent random noise that follows sub-Gaussian distributions with zero mean and bounded variance.

# Investigating the Effects of Overparameterization on IRM

## Setting

We aim to learn a linear model to predict  $y$  based on  $\mathbf{x}$ :

$$f(\mathbf{x}; \mathbf{w}) = (\Phi \circ \mathbf{x})^\top \mathbf{v} + b, \quad (1)$$

where  $\Phi \in \{0, 1\}^{d_{inv}+d_s+d_r}$  is a binary vector to perform feature selection .  $\mathbf{v} \in \mathbb{R}^{d_{inv}+d_s+d_r}$  is the parameter of the linear function on the top of  $\Phi$ .

We denote the  $\hat{\mathcal{L}}(\Phi)$  as loss of a given  $\Phi$  when  $\mathbf{v}$  is solved optimally,  $\hat{\mathcal{L}}(\Phi) := \min_{\mathbf{v}} \mathcal{L}(\mathbf{w})$ .

The ideal feature selector is  $\Phi_{inv} = [\mathbf{1}^{d_{inv}}, \mathbf{0}^{d_s+d_r}]$ , merely selecting the invariant feature  $\mathbf{x}_{inv}$  and discarding spurious features  $\mathbf{x}_s$  and random features  $\mathbf{x}_r$ . IRM learns  $\mathbf{w}$  by minimizing  $\mathcal{L}(\mathbf{w})$ , therefore, it can finally find the ideal feature selector  $\Phi_{inv}$  if and only if the following condition holds

$$\hat{\mathcal{L}}(\Phi_{inv}) < \hat{\mathcal{L}}(\Phi), \forall \Phi \neq \Phi_{inv}. \quad (2)$$

# Investigating the Effects of Overparameterization on IRM

## Proposition

(Failure of IRM in Overparameterization Region). If  $d_{inv} + d_s + d_r > n_{e_1} + n_{e_2}$ , then

$$\hat{\mathcal{L}}(\Phi_{all}) = 0 \leq \hat{\mathcal{L}}(\Phi_{inv}), \quad (3)$$

where  $\Phi_{all} = \mathbf{1}^{d_{inv}+d_s+d_r}$ .

## Corollary

(Worse Case) If  $d_s + d_r > n_{e_1} + n_{e_2}$ , then

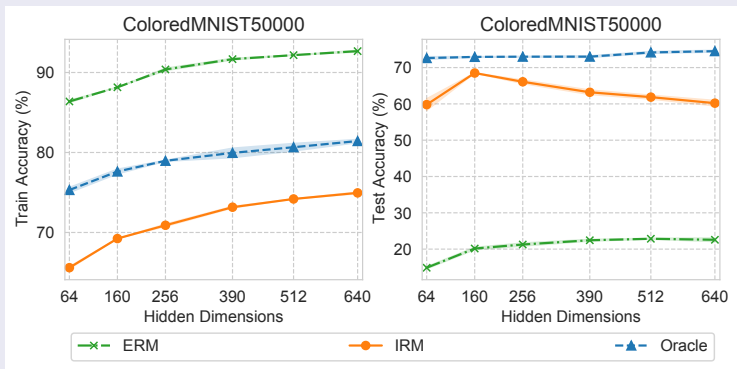
$$\hat{\mathcal{L}}(\Phi_{all}) = \hat{\mathcal{L}}(\Phi_{sr}) = 0 \leq \hat{\mathcal{L}}(\Phi_{inv}) \quad (4)$$

where  $\Phi_{sr} = [\mathbf{0}^{d_{inv}}, \mathbf{1}^{d_s+d_r}]$ .

# Investigating the Effects of Overparameterization on IRM

## Empirical Verification

As the hidden dimension increases, the training and testing accuracy of ERM and Oracle increases steadily. However, the testing accuracy of IRM decreases while its training accuracy increases.

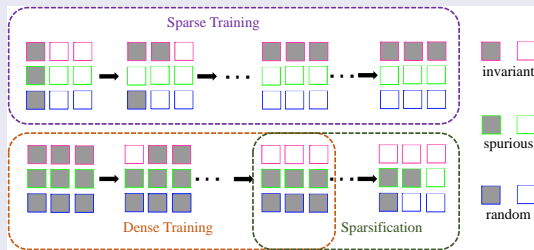


# Our Method

## SparseIRM

$$\begin{aligned} \min_{\mathbf{w}, \mathbf{s}} \quad & \mathbb{E}_{p(\mathbf{m}|\mathbf{s})} \mathcal{L}(\{\mathbf{v}, \mathbf{m} \circ \Phi\}) \\ \text{s.t. } \quad & \mathbf{w} \in \mathbb{R}^{d_w}, \mathbf{s} \in \mathcal{S} := \{\mathbf{s} \in [0, 1]^{d_\Phi} : \mathbf{1}^\top \mathbf{s} \leq K\}. \end{aligned} \quad (5)$$

## FlowChart



# Understanding the Benefits of SparselRM through Theoretical Analysis

## Theorem

*Under assumptions specified in Appendix B.6.2, assume  $n_{e_1} = n_{e_2} = n$ , if  $n > Q_1 + Q_2 \ln(d/\delta)$  and choosing  $K = d_{inv}$ , then with probability at least  $1 - \delta$  the following inequality holds:*

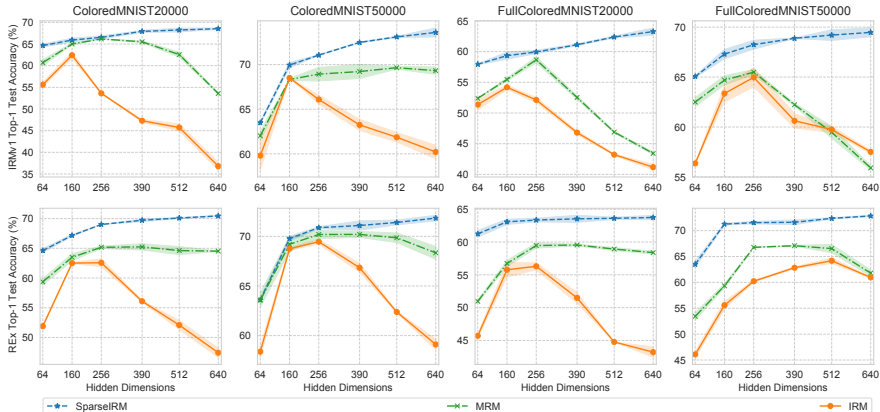
$$\hat{\mathcal{L}}(\Phi_{inv}) < \hat{\mathcal{L}}(\Phi), \forall \Phi \neq \Phi_{inv} \text{ and } \|\Phi\|_1 \leq K, \quad (6)$$

*where  $Q_1$  and  $Q_2$  are constants specified in the appendix.*

Theorem 1 indicates that in the linear case, SparselRM can provably find the invariant features as long as the number of the data samples is larger than a logarithmic term of spurious and random features.

The sparsity constraint limits the number of features to be selected, in which way any combinations of spurious or random features not exceeding the constraint will only lead to a larger loss.

# Experiments: ColoredMNIST



# Experiments: ColoredObject/CIFARMNIST and Ablation Studies

Table 3. Comparison of Top-1 Test Accuracy on ResNet-18 on ColoredObject and CIFARMNIST.

Dataset	ColoredObject	CIFARMNIST	
Oracle	$87.9 \pm 0.3$	$83.7 \pm 1.5$	
ERM	$51.6 \pm 0.5$	$39.5 \pm 0.4$	
SparseERM	$54.4 \pm 0.4$	$40.1 \pm 0.8$	
BayesianIRM	$78.1 \pm 0.6$	$59.3 \pm 0.8$	
IRMv1	IRM	$72.5 \pm 2.3$	$51.3 \pm 3.0$
	MRM	$58.4 \pm 0.9$	$56.7 \pm 2.3$
	SparseIRM	<b><math>87.4 \pm 0.6</math></b>	<b><math>63.9 \pm 0.4</math></b>
REx	IRM	$73.8 \pm 1.3$	$50.1 \pm 2.2$
	MRM	$55.7 \pm 2.9$	$52.6 \pm 1.5$
	SparseIRM	<b><math>80.3 \pm 1.1</math></b>	<b><math>62.7 \pm 0.6</math></b>

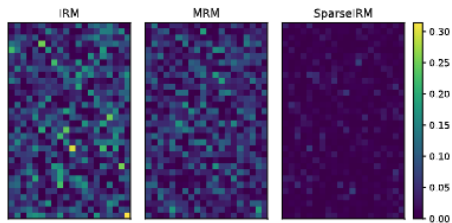


Figure 4. Comparison of absolute value of difference of feature representations by flipping spurious features. The dimension of feature representation 640 and we reshape it into  $32 \times 20$  matrix for better visualization.